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FDS4675

## 40V P-Channel PowerTrench$^{\text{Ò}}$ MOSFET

General Description

This P-Channel MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications requiring a wide range of gave drive voltage ratings (4.5V – 20V).

Applications

- Power management
- Load switch
- Battery protection

Features

- −11 A, −40 V $R_{DS(ON)} = 0.013\ \Omega$ @ $V_{GS} = -10$ V
  $R_{DS(ON)} = 0.017\ \Omega$ @ $V_{GS} = -4.5$ V

- Fast switching speed

- High performance trench technology for extremely low $R_{DS(ON)}$

- High power and current handling capability

SO-8

Pin 1

D D D D S S S S G
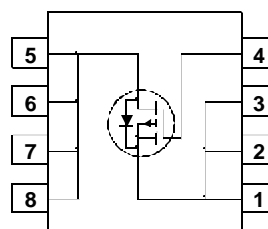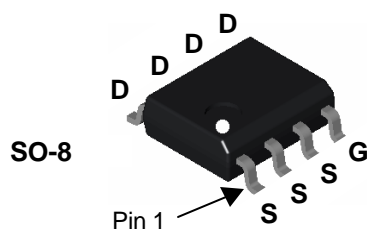
Absolute Maximum Ratings $T_A=25^{o}C$ unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		−40	V
V_{GSS}	Gate-Source Voltage		±20	V
I_D	Drain Current – Continuous	(Note 1a)	−11	A
	– Pulsed		−50	
P_D	Power Dissipation for Single Operation	(Note 1a)	2.4 (steady state)	W
		(Note 1b)	1.4	
		(Note 1c)	1.2	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		-55 to +175	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	62.5 (steady state), 50 (10 sec)	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	125	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS4675	FDS4675	13"	12mm	2500 units

Electrical Characteristics $T_A = 25°C$ unless otherwise noted

| Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0$ V, $I_D = -250$ μA	–40			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250$ μA, Referenced to 25°C		–34		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -32$ V, $V_{GS} = 0$ V			–1	μA
I_{GSSF}	Gate–Body Leakage, Forward	$V_{GS} = 20$ V, $V_{DS} = 0$ V			100	nA
I_{GSSR}	Gate–Body Leakage, Reverse	$V_{GS} = -20$ V $V_{DS} = 0$ V			–100	nA
On Characteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = -250$ μA	–1	–1.4	–3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250$ μA, Referenced to 25°C		4.6		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	$V_{GS} = -10$ V, $I_D = -11$ A		10	13	mΩ
		$V_{GS} = -4.5$ V, $I_D = -9.5$ A		13	17	
		$V_{GS} = -10$ V, $I_D = -11$ A, $T_J = 125°C$		15	21	
$I_{D(on)}$	On–State Drain Current	$V_{GS} = -10$ V, $V_{DS} = -5$ V	–25			A
g_{FS}	Forward Transconductance	$V_{DS} = -5$ V, $I_D = -11$ A		44		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = -20$ V, $V_{GS} = 0$ V,		4350		pF
C_{oss}	Output Capacitance	$f = 1.0$ MHz		622		pF
C_{rss}	Reverse Transfer Capacitance			290		pF
Switching Characteristics (Note 2)						
$t_{d(on)}$	Turn–On Delay Time	$V_{DD} = -20$ V, $I_D = -1$ A,		20	36	ns
t_r	Turn–On Rise Time	$V_{GS} = -4.5$ V, $R_{GEN} = 6$ Ω		29	46	ns
$t_{d(off)}$	Turn–Off Delay Time			95	152	ns
t_f	Turn–Off Fall Time			60	96	ns
Q_g	Total Gate Charge	$V_{DS} = -20$ V, $I_D = -11$ A,		40	56	nC
Q_{gs}	Gate–Source Charge	$V_{GS} = -4.5$ V		11		nC
Q_{gd}	Gate–Drain Charge			13		nC
Drain–Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain–Source Diode Forward Current				–2.1	A
V_{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0$ V, $I_S = -2.1$ A (Note 2)		–0.7	–1.2	V

Notes:

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.
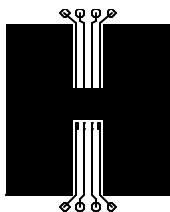
a) 50°C/W when mounted on a 1in^2 pad of 2 oz copper
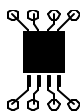
b) 105°C/W when mounted on a .04 in^2 pad of 2 oz copper
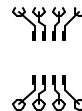
c) 125°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%
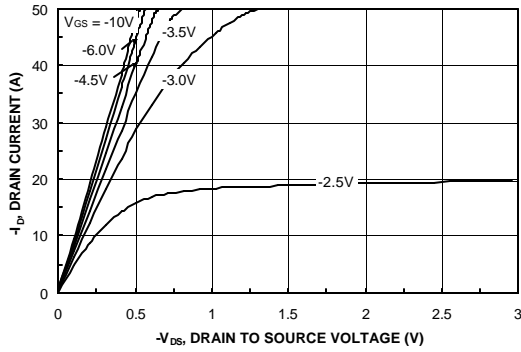
Typical Characteristics

Figure 1. On-Region Characteristics.
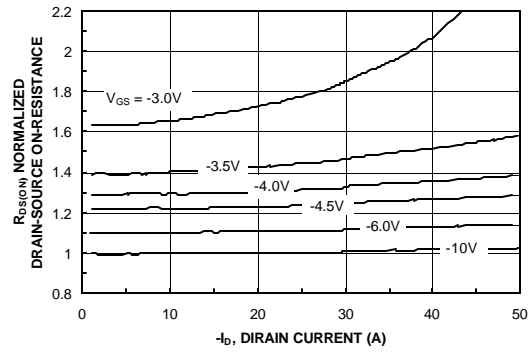

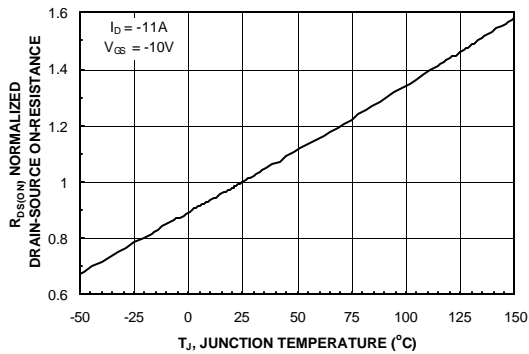**Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.**

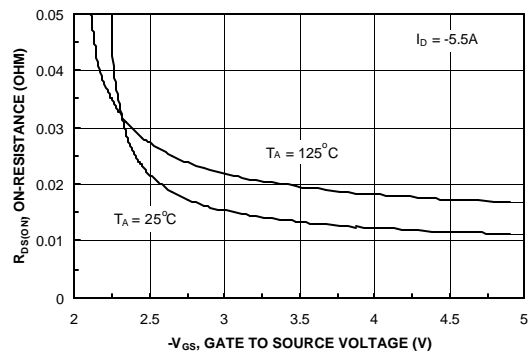**Figure 3. On-Resistance Variation with Temperature.**

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.
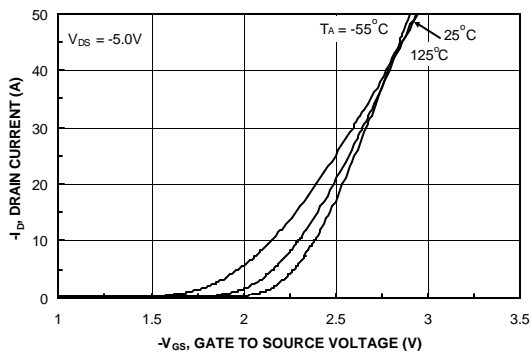

Figure 5. Transfer Characteristics.
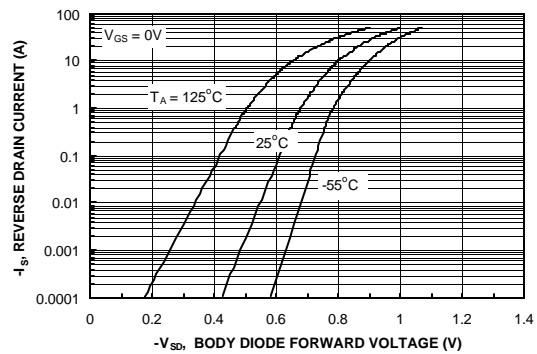
Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics

Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.

Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c.
Transient thermal response will change depending on the circuit board design.

TRADEMARKS

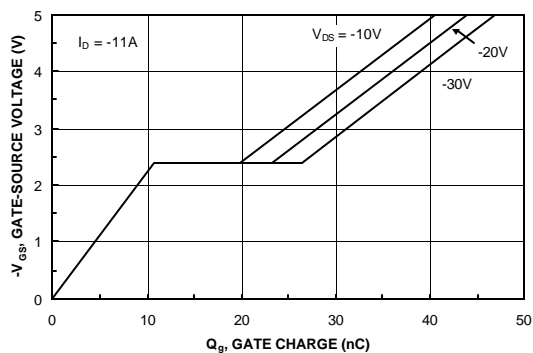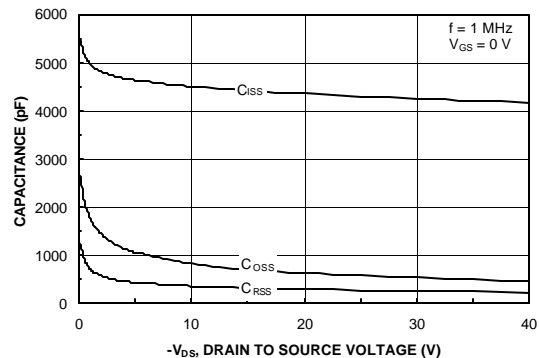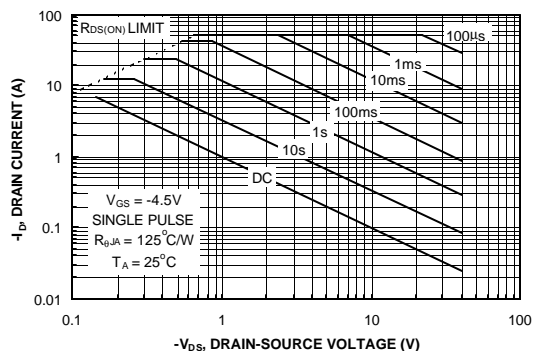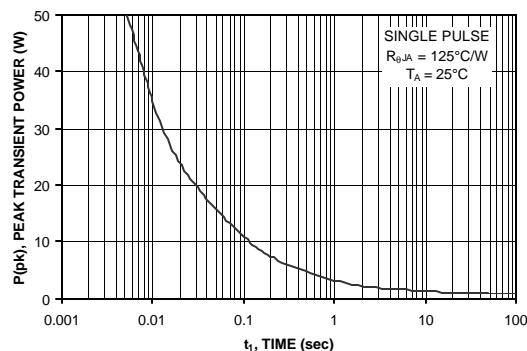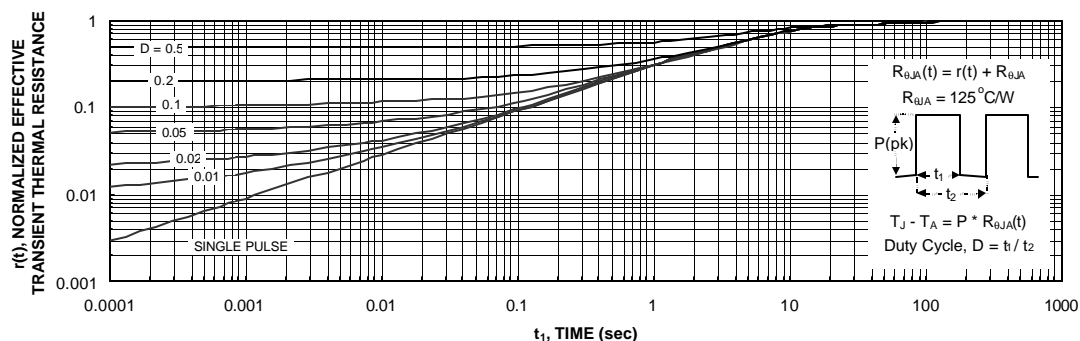The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

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